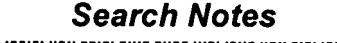


Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/563,824	TSUCHIYA ET AL.
Examiner	Art Unit	
Christian A. Hannon	2618	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner